

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

YOEL, et al.

Confirmation No. 4532

Appl. No. 10/606,199

Art Unit: 2877

Filed: June 26, 2003

Examiner: PUNNOOSE, Roy M.

For: THIN FILMS MEASUREMENT METHOD AND SYSTEM

RESPONSE UNDER 37 C.F.R. 1.111

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Commissioner:

This is in response to the Office Action having a mailing date of October 19, 2005. The three-month shortened statutory period to respond was set to expire January 19, 2006. Applicants petition for a three (3) month extension of time to April 19, 2006.

In view of the following remarks, Applicants respectfully request that the Examiner reconsider and withdraw the outstanding rejection and allow this application.

Remarks begin on page 2 of this paper.